7-18-03

FORM PTO-1449 (SUBSTITUTE)				Attorney Docket No.: M&N-IT-466 Appl. No.:					
U.S. DEPARTMI			Appl. No.: 10 623067						
PATENT AND TRADEMARK OFFICE				Applicant: EDIC LIALL					
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Applicant: ERIC LIAU					
(37 CFR 1.98(b))				Filing Date: July 18, 2003					
	<u> </u>			Group Art Unit:	38D	5			
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB	FILI		
INTIALO	Α	TAILIN NO.	DAIL	TATEMEE	OLASS	CLAGG	<u> </u>	12	
	В								
····	С								
	D								
_	E		-						
	F	·							
	G	·							
	Н	:							
•		•							
		FOREIG	ON PATE	NT DOCUMENT					
-		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRAI YES		
<del></del>	J	DOCOMENT NO.	DAIL	COOMINI	CLASS	CLASS	123	INO	
	К					<u> </u>			
	L								
-	М								
	Ν								
ОТН	ER DO	OCUMENTS (Inclu	iding Autl	hor, Title, Date, Pe	rtinent Pa	iges, etc.	) .		
BT		Traversal*, Europe	an Design	ial Circuit Test Gene and Test Conference	ce, March	1997, pp.	22-28	e	
BT		Singer, S. et al.: "V Lakehurst, May 5,		t Automation General 1-10	itor (VTAG	i)", Navair			
EXAMINER	A	Mas	-	DATE CONSIDI	RED				
-			•	hether or not cita					
		•		if not in conformation in the conformation to application to application in the conformation in the confor		not con	sider	ea.	
ordao oopy	<u> </u>	O TOTAL WILLIAM	COMMINICAL	noution to applied		<del></del>			

7-18-03

FORM PTO-1449 (SUBSTITUTE)				Attorney Docket No.: M&N-IT-466 Appl. No.:					
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				Appl. No.: 12 623067					
INFORMATION DISCLOSURE				Applicant: ERIC LIAU					
		T BY APPLICAN	Filing Date: July 18, 2003 Group Art Unit: 2826						
(	(37 C	FR 1.98(b))							
	_	<del></del>			000			$\dashv$	
				•					
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB . CLASS	FILI DA	- ,	
	Α								
	В								
	С								
	D								
	E								
	F								
	G								
	Н								
	1							$\overline{}$	
	ı •	•		l	<u> </u>			1	
	L <u>.                                    </u>	FOREIC	SN PATE	NT DOCUMENT	.l	<u> </u>	. ·		
	•	FOREIC	OATE	NT DOCUMENT	CLASS	SUB CLASS	TRAI YES		
	J	•			CLASS				
		•			CLASS				
	J	•			CLASS				
	J K	•			CLASS				
	J K L	•			CLASS				
ОТН	J K L M	DOCUMENT NO.	DATE			CLASS	YES		
	J K L M	DOCUMENT NO.  COUMENTS (Inclu	DATE	hor, Title, Date, Penatic Test Generation	ertinent Pa	cLASS  ages, etc.	YES  ) ms for	I NO	
отн <i>В</i> Т	J K L M	DOCUMENT NO.  COUMENTS (Inclu	DATE  uding Aut  al.: "Auton  out and Te	hor, Title, Date, Penatic Test Generationst Automation", Pren	ertinent Pa	cLASS  ages, etc.	YES  ) ms for	I NO	
	J K L M	DOCUMENT NO.  COUMENTS (Included Rudnick, E. M. et a VLSI Design, Layo	DATE  uding Aut  al.: "Auton  out and Te	hor, Title, Date, Penatic Test Generationst Automation", Pren	ertinent Pa	cLASS  ages, etc.	YES  ) ms for	I NO	
	J K L M	DOCUMENT NO.  COUMENTS (Included Rudnick, E. M. et a VLSI Design, Layo	DATE  uding Aut  al.: "Auton  out and Te	hor, Title, Date, Penatic Test Generationst Automation", Pren	ertinent Pa n", "Genetiontice Hall, U	cLASS  ages, etc.	YES  ) ms for	I NO	
81 EXAMINER	J K L M N ER DO	DOCUMENT NO.  COUMENTS (Included in the country of	DATE  uding Aut  al.: "Auton  put and Te  -166 and	hor, Title, Date, Penatic Test Generationst Automation", Prerpp. 179-184  DATE CONSID	ertinent Pann", "Genetichtice Hall, U	eges, etc.	YES  )  ms for Idle Ri	iver,	
EXAMINER: with MPEP 6	J K L M N ER DO	DOCUMENT NO.  COMENTS (Inclu Rudnick, E. M. et a VLSI Design, Layo NY, 1999, pp. 159  If citation consideraw line through	DATE  uding Auton put and Te -166 and idered, v	hor, Title, Date, Penatic Test Generationst Automation*, Prerpp. 179-184	ertinent Pan", "Genetinitice Hall, U	eges, etc.	YES  ) ns for idle Ri	iver,	